

Supplementary Materials: Prediction of a Two-Transistor Vertical QNOT Gate

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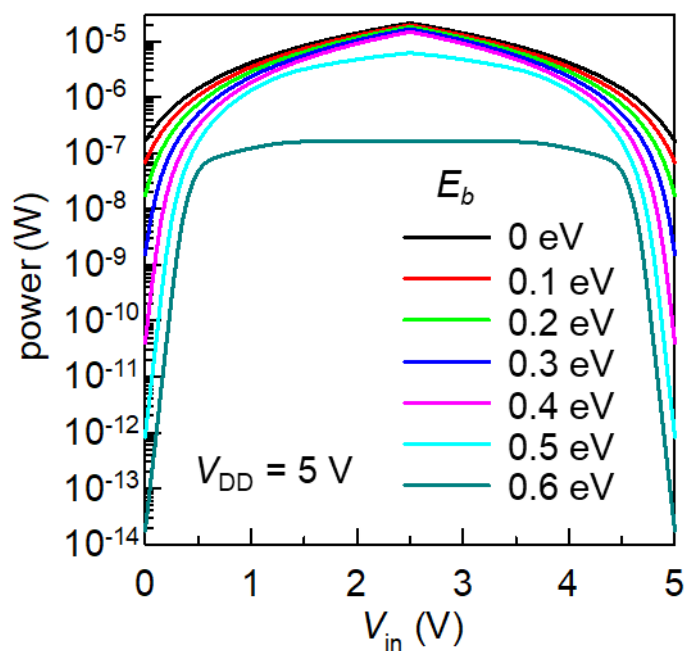


Figure S1. Power consumption.

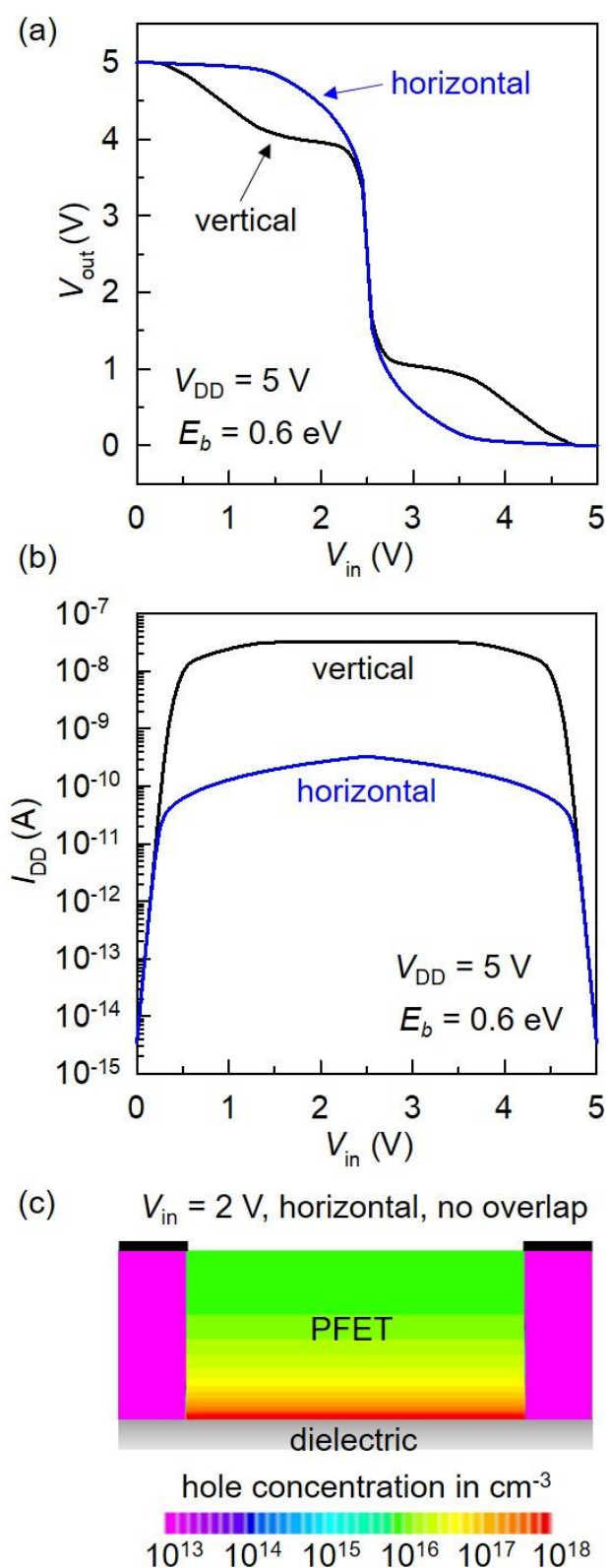


Figure S2. Vertical and horizontal inverter comparison: (a) VTC, (b) IDD comparison. (c) Hole concentration inside the PFET at $V_{in} = 2$ V (level “2”) in the horizontal inverter.

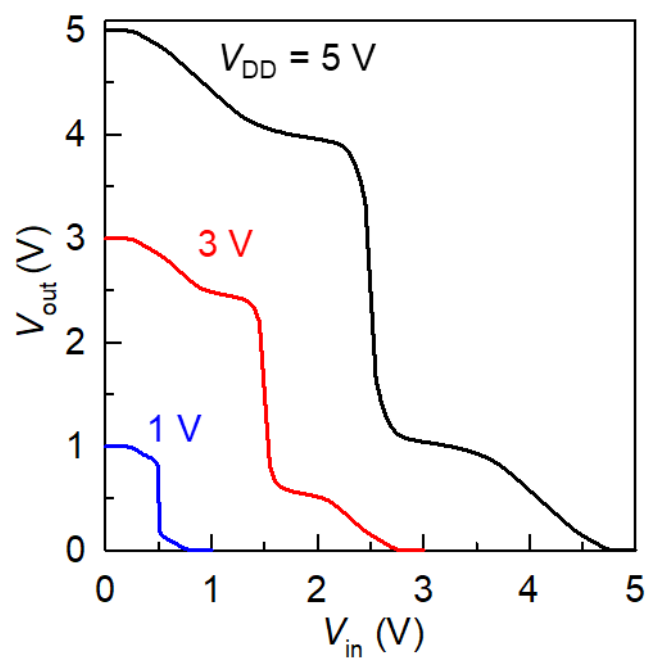


Figure S3. Scaling property.